


<b>Search Notes</b> 	<b>Application/Control No.</b> 10773496	<b>Applicant(s)/Patent Under Reexamination</b> CHAN ET AL.
	<b>Examiner</b> Myhre, James W	<b>Art Unit</b> 3622

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search (USPAT, US PgPub, JPO, EPO, DERWENT, IBM TB) (attached)	1/4/08	JWM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner